EXAMINER	Lut 1	m	DATE CONSIDERED	1/5/05
*EXAMINER:			conformance with MPEP 609; Dr	

FORM PTO-1449

S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

2816

December 23, 2003

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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W	AB	6,294,936 B1	September 25, 2001	Daniel M. CLEMENTI	327	116	May 13, 2002
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W 7	АМ	7-202652	April 8, 1995	Japan				x	

AN

AD

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EXAMINER	and I	m	DATE CONSIDERED	1/5/05		
*EXAMINER:	Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					